

<b>Notice of References Cited</b>	Application/Control No. 10/511,022	Applicant(s)/Patent Under Reexamination GRUNER ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,587,901 B2	07-2003	Nishikawa et al.	710/100
*	B	US-5,920,197 A	07-1999	Price et al.	324/538
*	C	US-6,751,740 B1	06-2004	Robertson et al.	713/300
*	D	US-6,577,230 B1	06-2003	Wendt et al.	375/258
*	E	US-5,081,648 A	01-1992	Herzog, Hans K.	375/258
*	F	US-6,128,661 A	10-2000	Flanagin et al.	709/227
*	G	US-6,385,667 B1	05-2002	Estakhri et al.	710/8
*	H	US-6,363,437 B1	03-2002	Ptasinski et al.	710/10
*	I	US-5,163,048 A	11-1992	Heutink, Frederick H.	370/402
*	J	US-6,950,610 B2	09-2005	Lee, Seung-ill	398/141
*	K	US-6,302,741 B1	10-2001	Fasold et al.	439/620
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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